



Report No.:SZ14060161E01

FCC TEST REPORT



Issued to

SGP Technologies S.A.

For

Smartphone

Model Name: BP1
Trade Name: N/A
Brand Name: blackphone
FCC ID: 2ACDKBP1
Standard: 47 CFR Part 15 Subpart B
Test date: June 24, 2014 – July 18, 2014
Issue date: July 18, 2014

By

Shenzhen Morlab Communications Technology Co., Ltd.

FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District,
ShenZhen, Guangdong Province, P. R. China 518101

Tested by Xiao Xiong
Xiao Xiong
(Test Engineer)

Date 2014.7.18



Approved by Zeng Dexin
Zeng Dexin
(Chief Engineer)

Date 2014.7.18

Review by Huang Pulong
Huang Pulong
(EMC Manager)

Date 2014.7.18

The report refers only to the sample tested and does not apply to the bulk. This report is issued in confidence to the client and it will be strictly treated as such by the Shenzhen MORLAB Communication Technology Co., Ltd. It may not be reproduced rather in its entirety or in part and it may not be used for advertising. The client to whom the report is issued may, however, show or send it, or a certified copy thereof prepared by the Shenzhen MORLAB Telecommunication Co., Ltd to his customer. Supplier or others persons directly concerned. Shenzhen MORLAB Telecommunication Co., Ltd will not, without the consent of the client enter into any discussion of correspondence with any third party concerning the contents of the report. In the event of the improper use of the report, Shenzhen MORLAB Telecommunication Co., Ltd reserves the rights to withdraw it and to adopt any other remedies which may be appropriate

Shenzhen Morlab Communications Technology Co., Ltd.

Web site: <http://www.morlab.cn/>

Phone: +86 (0) 755 36698555

Fax: +86 (0) 755 36698525

TABLE OF CONTENTS

1. GENERAL INFORMATION	3
1.1 EUT DESCRIPTION.....	3
1.2 TEST STANDARDS AND RESULTS	4
1.3 FACILITIES AND ACCREDITATIONS	5
1.3.1 FACILITIES	5
1.3.2 ENVIRONMENTAL CONDITIONS	5
1.3.3 MEASUREMENT UNCERTAINTY	5
2. TEST CONDITIONS SETTING	6
2.1 TEST MODE	6
2.2 TEST SETUP AND EQUIPMENTS LIST.....	7
2.2.1 CONDUCTED EMISSION.....	7
2.2.2 RADIATED EMISSION	8
3. 47 CFR PART 15B REQUIREMENTS	10
3.1 CONDUCTED EMISSION	10
3.1.1 REQUIREMENT	10
3.1.2 TEST DESCRIPTION	10
3.1.3 TEST RESULT.....	10
3.2 RADIATED EMISSION	13
3.2.1 REQUIREMENT	13
3.2.2 TEST DESCRIPTION	13
3.2.3 FREQUENCY RANGE OF MEASUREMENT	13
3.2.4 TEST RESULT.....	14

Change History		
Issue	Date	Reason for change
1.0	July 18, 2014	First edition

1. GENERAL INFORMATION

1.1 EUT Description

EUT Type:	Smartphone
Serial No:	(n.a., marked #1 by test site)
Hardware Version:	1.0
Software Version:	V07
Applicant:	SGP Technologies S.A. Rue du 31 Decembre, 47, Geneva, Switzerland.
Manufacturer:	Tinno Mobile Technology Corp. 4/F., H-3 Building, OCT Eastern Industrial Park. NO.1 XiangShan East Road., Nan Shan District, Shenzhen, P.R. China.

Power supply:	Battery	
	Brand Name:	blackphone
	Model No.:	BP1
	Serial No.:	(n.a. marked #1 by test site)
	Capacity:	2000mAh
	Rated Voltage:	3.7V
	Charge Limit:	4.2V
Ancillary Equipment:	AC Adapter (Charger for Battery)	
	Brand Name:	N/A
	Model No.:	PSAI05R-050Q
	Serial No.:	(n.a. marked #1 by test site)
	Rated Input:	~ 100-240V, 50/60Hz, 300mA
	Rated Output:	= 5V, 1000mA

NOTE:

1. The EUT is a Smartphone. It is equipped with a T-Flash card slot, a Micro-B USB port which can be connected to the ancillary equipments e.g. the PC.
2. For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.

1.2 Test Standards and Results

The objective of the report is to perform testing according to 47 CFR Part 15 Subpart B:

No.	Identity	Document Title
1	47 CFR Part 15(10-1-13 Edition)	Radio Frequency Devices

Test detailed items/section required by FCC rules and results are as below:

No.	Section	Description	Result
1	15.107	Conducted Emission	PASS
2	15.109	Radiated Emission	PASS

NOTE: The tests were performed according to the method of measurements prescribed in ANSI C63.4-2009.

1.3 Facilities and Accreditations

1.3.1 Facilities

Shenzhen Morlab Communications Technology Co., Ltd. Morlab Laboratory is a testing organization accredited by China National Accreditation Service for Conformity Assessment (CNAS) according to ISO/IEC 17025. The accreditation certificate number is L3572.

All measurement facilities used to collect the measurement data are located at FL.3, Building A, FeiYang Science Park, No.8 LongChang Road, Block 67, BaoAn District, ShenZhen, GuangDong Province, P. R. China 518101. The test site is constructed in conformance with the requirements of ANSI C63.4-2009 and CISPR Publication 22:2008; the FCC registration number is 695796.

1.3.2 Environmental Conditions

During the measurement, the environmental conditions were within the listed ranges:

Temperature (°C):	15 - 35
Relative Humidity (%):	30 - 60
Atmospheric Pressure (kPa):	86 -106

1.3.3 Measurement Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

Uncertainty of Conducted Emission:	±1.8dB
Uncertainty of Radiated Emission:	±3.1dB

2. TEST CONDITIONS SETTING

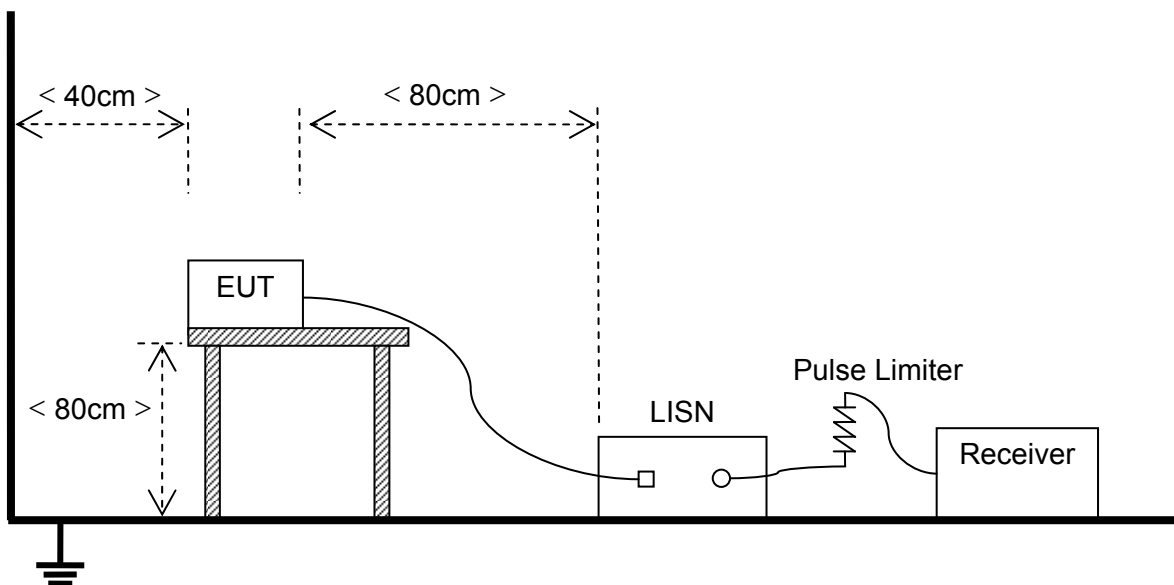
2.1 Test Mode

1	The first test mode (Data Transmission) The EUT configuration of the emission tests is EUT + Battery + T-Flash Card + PC. In this test mode, the EUT with a T-Flash Card embedded was connected to a PC via the Micro-B USB port. During the measurement, the data is transmitting between the PC and the T-Flash Card of the EUT.
2	The second test mode (Standby) The EUT configuration of the emission tests is EUT + Battery + Charger. During the measurement, the EUT was charged by its adapter and turned on.
Note: All test modes are performed, only the worst case(Data Transmission) is recorded in this report.	

2.2 Test Setup and Equipments List

2.2.1 Conducted Emission

A. Test Setup:



The EUT is placed on a 0.8m high insulating table, which stands on the grounded conducting floor, and keeps 0.4m away from the grounded conducting wall. The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. A Pulse Limiter is used to protect the measuring instrument. The factors of the whole test system are calibrated to correct the reading.

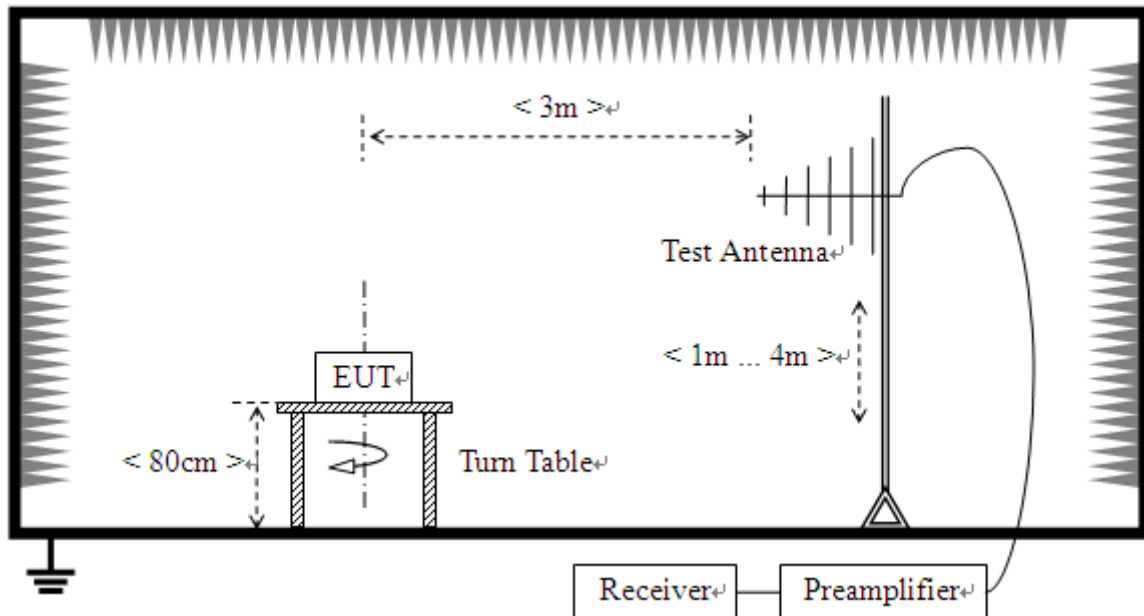
B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
Receiver	Narda	PMM 9010	595WX11007	2014.2.21	2015.2.20
EMC Analyzer	Agilent	E7405A	US44210471	2014.2.21	2015.2.20
LISN	Schwarzbeck	NSLK 8127	812744	2014.2.24	2015.2.23
Pulse Limiter (20dB)	Schwarzbeck	VTSD 9561-D	9391	(n.a.)	(n.a.)
System Simulator	Agilent	E5515C	GB43130131	2014.2.21	2015.2.20
PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)

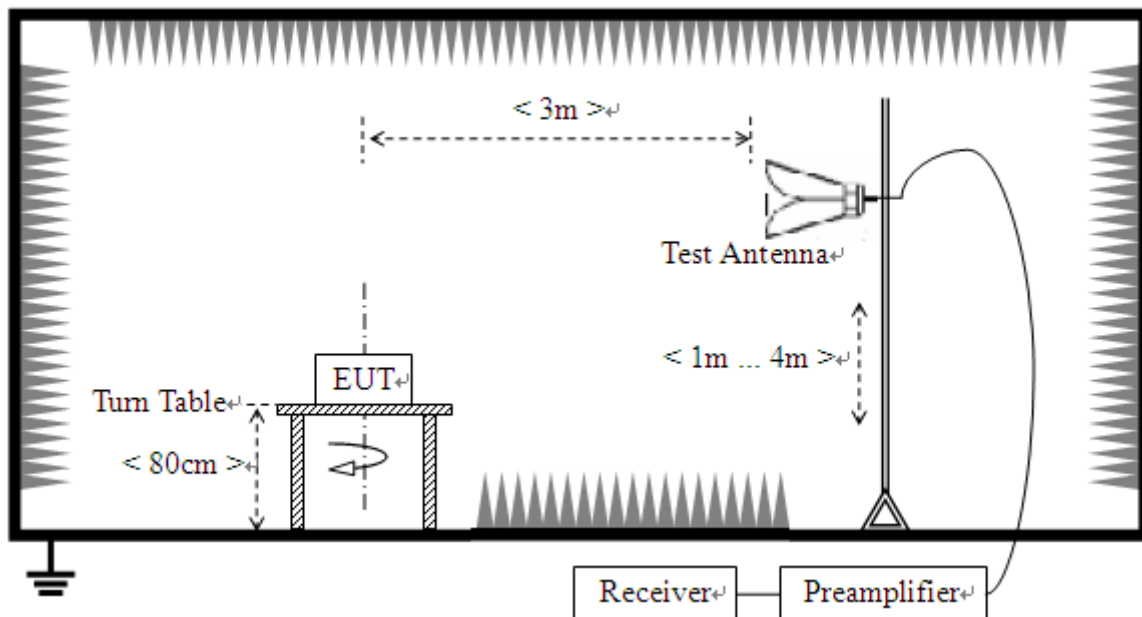
2.2.2 Radiated Emission

A. Test Setup:

- 1) For radiated emissions from 30MHz to 1GHz



- 2) For radiated emissions above 1GHz



The test is performed in a 3m Semi-Anechoic Chamber; the antenna factor, cable loss and so on of the site (factors) is calculated to correct the reading. The EUT is placed on a 0.8m high insulating Turn Table,

and keeps 3m away from the Test Antenna, which is mounted on a variable-height antenna master tower.

For the test Antenna:

In the frequency range above 30MHz, Bi-Log Test Antenna (30MHz to 1GHz) and Horn Test Antenna (above 1GHz) are used. Test Antenna is 3m away from the EUT. Test Antenna height is varied from 1m to 4m above the ground to determine the maximum value of the field strength. The emission levels at both horizontal and vertical polarizations should be tested.

B. Equipments List:

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
EMC Analyzer	Agilent	E7405A	US44210471	2014.2.21	2015.2.20
Receiver	Narda	PMM 9060	001WX11001	2014.2.21	2015.2.20
Receiver	Narda	PMM 9010	595WX11007	2014.2.21	2015.2.20
Semi-Anechoic Chamber	Albatross	9m*6m*6m	(n.a.)	2014.2.21	2015.2.20
Test Antenna - Bi-Log	Schwarzbeck	VULB 9163	9163-274	2014.2.25	2015.2.24
Test Antenna - Horn	Schwarzbeck	BBHA 9120D	9120D-963	2014.2.25	2015.2.24
PC	Lenovo	ThinkPadT61	ZZF3077	(n.a.)	(n.a.)

3. 47 CFR PART 15B REQUIREMENTS

3.1 Conducted Emission

3.1.1 Requirement

According to FCC section 15.107, the radio frequency voltage that is conducted back onto the AC power line on any frequency within the band 150kHz to 30MHz shall not exceed the limits in the following table, as measured using a 50 μ H/50 Ω line impedance stabilization network (LISN).

Frequency range (MHz)	Conducted Limit (dB μ V)	
	Quasi-peak	Average
0.15 - 0.50	66 to 56	56 to 46
0.50 - 5	56	46
5 - 30	60	50

NOTE:

- a) The limit subjects to the Class B digital device.
- b) The lower limit shall apply at the band edges.
- c) The limit decreases linearly with the logarithm of the frequency in the range 0.15 - 0.50MHz.

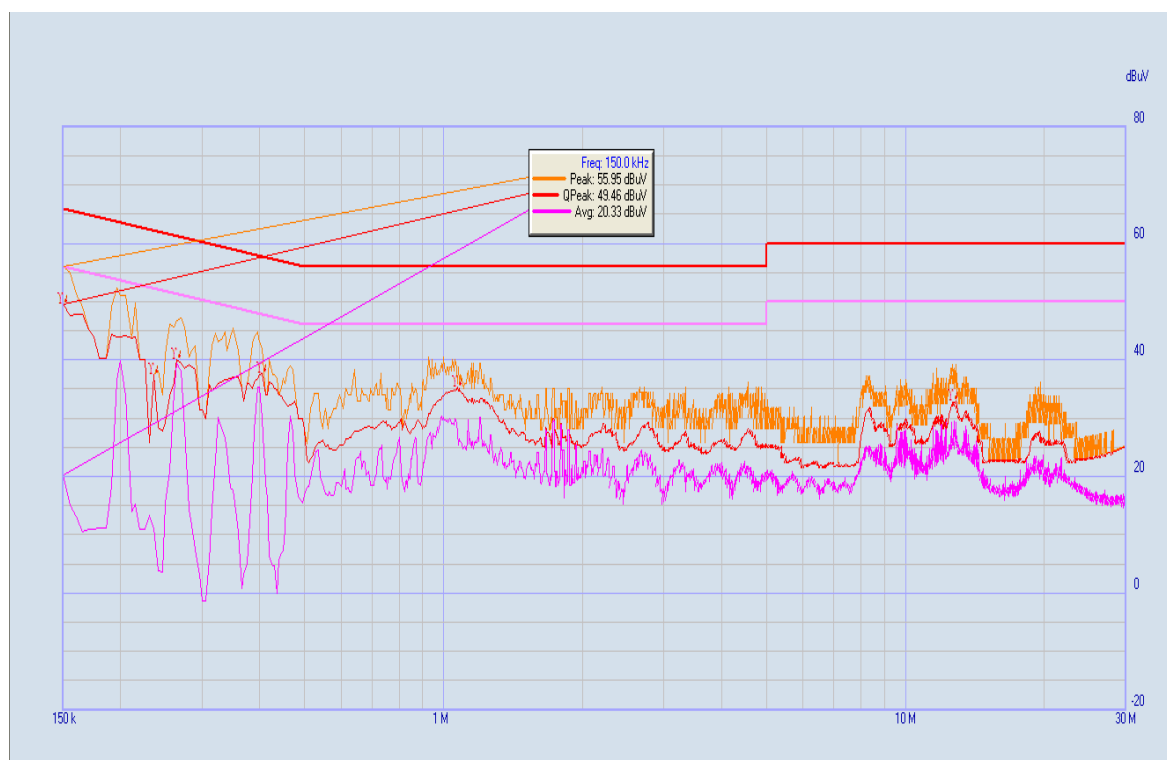
3.1.2 Test Description

See section 2.2.1 of this report.

3.1.3 Test Result

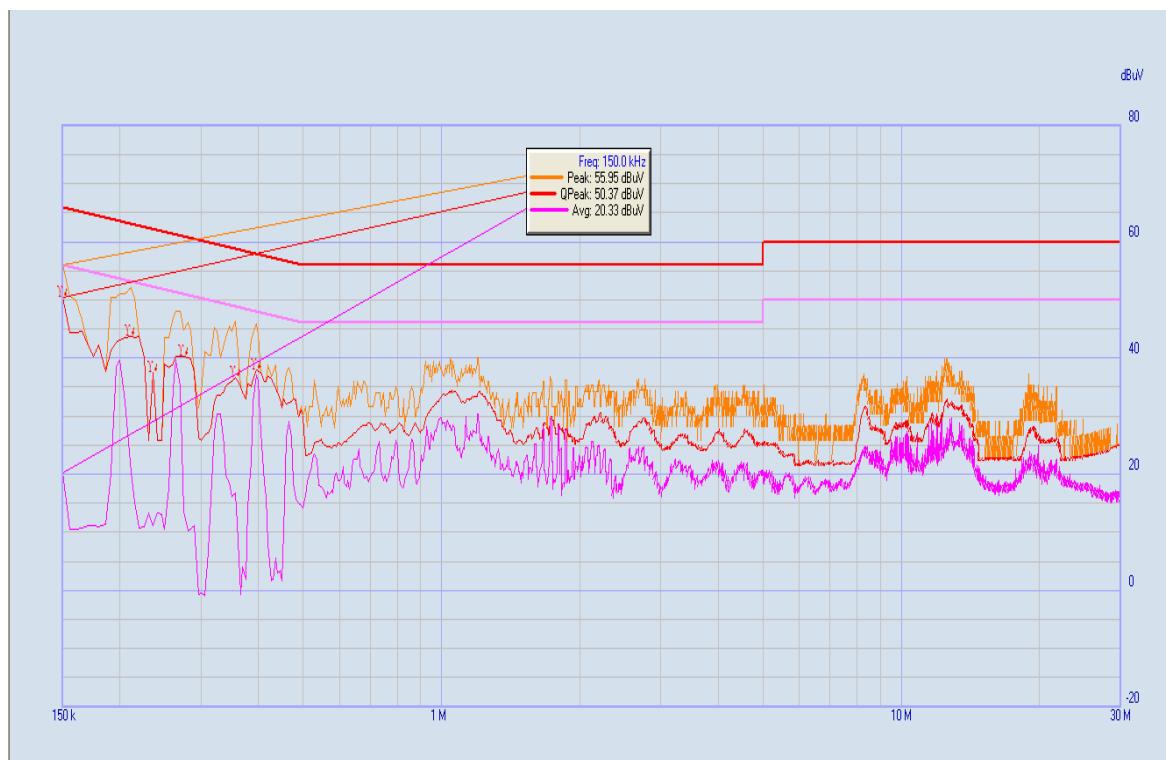
The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. All test modes are considered, refer to recorded points and plots below.

A. Test Plot and Suspicious Points:



(Plot A: L Phase)

NO.	Fre. (MHz)	Emission Level (dBμV)		Limit (dBμV)		Power-line	Verdict
		Quai-peak	Average	Quai-peak	Average		
1	0.15	49.46	20.33	66.00	56.00	Line	PASS
2	0.235	37.54	11.11	63.57	53.57		PASS
3	0.265	39.99	39.34	62.71	52.71		PASS
4	0.405	37.65	29.92	58.71	48.71		PASS
5	1.07	35.34	27.25	56.00	46.00		PASS
6	12.685	32.76	27.53	60.00	50.00		PASS



(Plot B: N Phase)

NO.	Fre. (MHz)	Emission Level (dBμV)		Limit (dBμV)		Power-line	Verdict
		Quai-peak	Average	Quai-peak	Average		
1	0.15	50.37	20.33	66.00	56.00	Neutral	PASS
2	0.21	43.72	20.46	64.29	54.29		PASS
3	0.235	37.54	11.11	63.57	53.57		PASS
4	0.275	40.35	13.50	62.43	52.43		PASS
5	0.355	36.57	16.86	60.14	50.14		PASS
6	0.395	37.89	37.04	59.00	49.00		PASS

Test Result: PASS

3.2 Radiated Emission

3.2.1 Requirement

According to FCC section 15.109(a), the field strength of radiated emissions from unintentional radiators at a distance of 3 meters shall not exceed the following values:

Frequency range (MHz)	Field Strength		Field Strength Limitation at 3m Measurement Dist	
	$\mu\text{V/m}$	Dist	$(\mu\text{V/m})$	$(\text{dB}\mu\text{V/m})$
30.0 - 88.0	100	3m	100	$20\log 100$
88.0 - 216.0	150	3m	150	$20\log 150$
216.0 - 960.0	200	3m	200	$20\log 200$
Above 960.0	500	3m	500	$20\log 500$

As shown in FCC section 15.35(b), for frequencies above 1000MHz, the field strength limits are based on average detector. When average radiated emission measurements are specified in this part, including emission measurements below 1000MHz, there also is a limit on the radio frequency emissions, as measured using instrumentation with a peak detector function, corresponding to 20dB above the maximum permitted average limit for the frequency being investigated unless a different peak emission limit is otherwise specified in the rules.

Note:

- 1) The tighter limit shall apply at the boundary between two frequency range.
- 2) Limitation expressed in $\text{dB}\mu\text{V/m}$ is calculated by $20\log \text{Emission Level}(\mu\text{V/m})$.
- 3) If measurement is made at 3m distance, then F.S Limitation at 3m distance is adjusted by using the formula of $L_{d1} = L_{d2} * (d_2/d_1)^2$.

Example:

F.S Limit at 30m distance is $30\mu\text{V/m}$, then F.S Limitation at 3m distance is adjusted as

$$L_{d1} = L_1 = 30\mu\text{V/m} * (10)^2 = 100 * 30\mu\text{V/m}$$

3.2.2 Test Description

See section 2.2.2 of this report.

3.2.3 Frequency range of measurement

Highest frequency generated or used in the device is the highest speed of the processor, lowest frequency generated or used in the device is the lowest frequency of the oscillator. According to 15.33(b)(1), the frequency range of radiated measurement for the EUT is listed in the following table:

Frequency	Frequency generated or used in the device	Frequency range of radiated measurement in the report
Highest	2GHz	10GHz

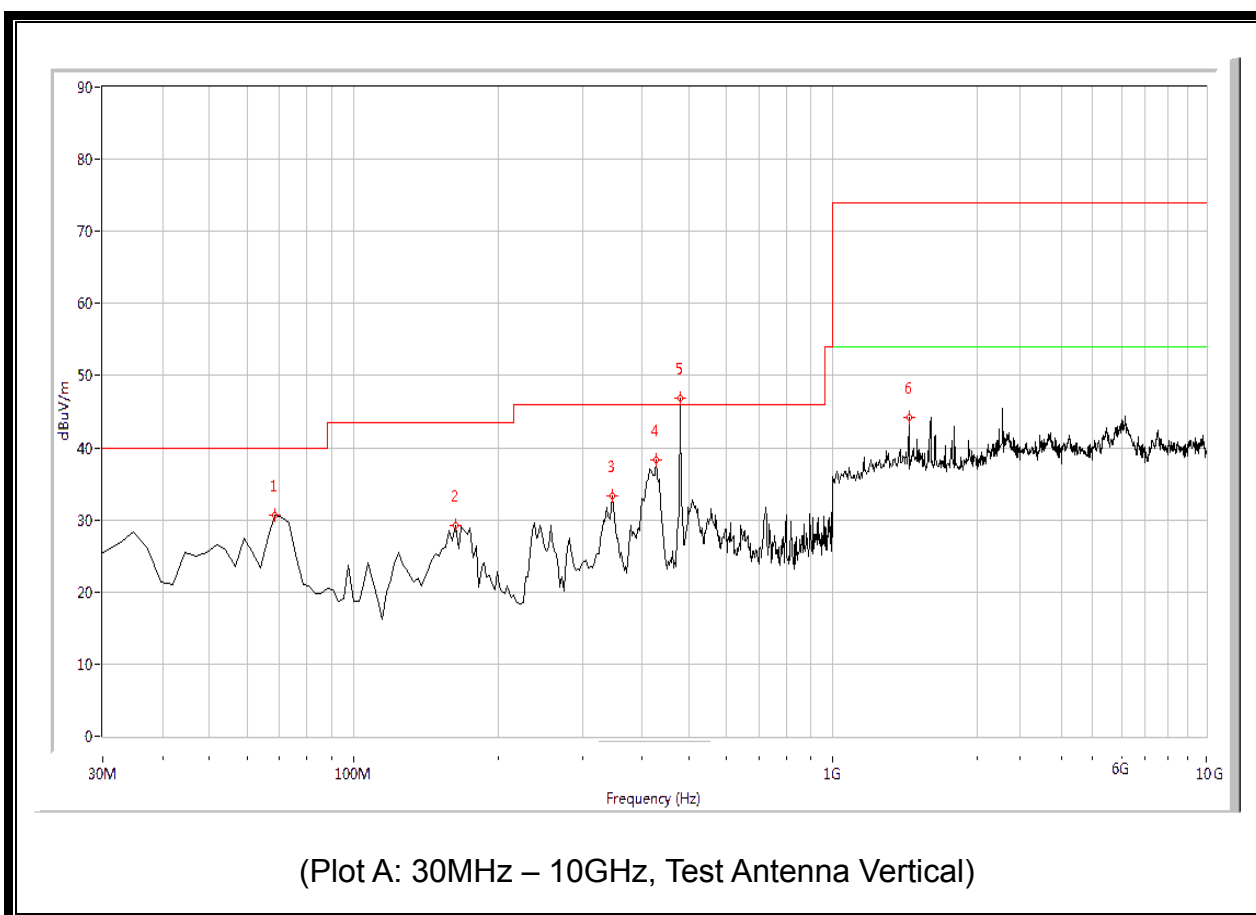
3.2.4 Test Result

The maximum radiated emission is searched using PK, QP and AV detectors; the emission levels more than the limits, and that have narrow margins from the limits will be re-measured with AV and QP detectors. Both the vertical and the horizontal polarizations of the Test Antenna are considered to perform the tests. All test modes are considered, refer to recorded points and plots below.

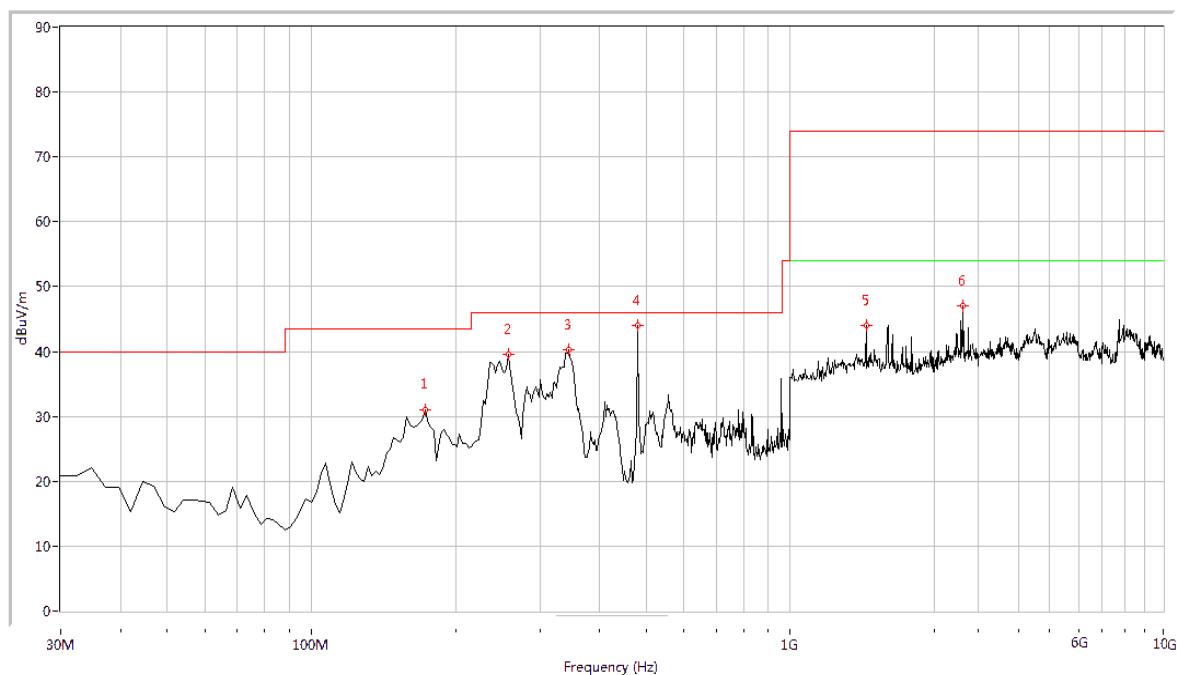
The amplitude of spurious emissions which are attenuated more than 20 dB below the permissible value need not be reported.

Note: All radiated emission tests were performed in X, Y, Z axis direction, and only the worst axis test condition was recorded in this test report.

A. Test Plots and Suspicious Points:



NO.	Fre. (MHz)	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	Antenna	Verdict
1	68.703	N.A	30.62	N.A	N.A	40.0	N.A	Vertical	Pass
2	163.042	N.A	29.22	N.A	N.A	43.5	N.A	Vertical	Pass
3	346.883	N.A	33.25	N.A	N.A	46.0	N.A	Vertical	Pass
4	426.708	N.A	38.38	N.A	N.A	46.0	N.A	Vertical	Pass
5	479.925	N.A	44.47	N.A	N.A	46.0	N.A	Vertical	Pass
6	1438.903	44.11	N.A	39.05	74.0	N.A	54.0	Vertical	Pass



(Plot B: 30MHz – 10GHz, Test Antenna Horizontal)

NO.	Fre. (MHz)	Pk	QP	AV	Limit-PK	Limit-QP	Limit-AV	Antenna	Verdict
1	172.718	N.A	30.95	N.A	N.A	43.5	N.A	Horizontal	Pass
2	257.382	N.A	39.48	N.A	N.A	46.0	N.A	Horizontal	Pass
3	344.464	N.A	40.23	N.A	N.A	46.0	N.A	Horizontal	Pass
4	479.925	N.A	42.59	N.A	N.A	46.0	N.A	Horizontal	Pass
5	1438.903	44.00	N.A	38.64	74.0	N.A	54.0	Horizontal	Pass
6	2596.758	47.12	N.A	41.78	74.0	N.A	54.0	Horizontal	Pass

Test Result: PASS

****END OF REPORT ****